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April 1999

FDN335N

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FDN335N N-Channel 2.5V Specified PowerTrench[™] MOSFET

General Description

This N-Channel 2.5V specified MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain low gate charge for superior switching performance.

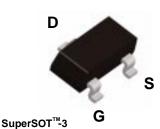
Applications

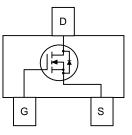
• DC/DC converter

Load switch

Features

- 1.7 A, 20 V. $R_{DS(ON)} = 0.07 \Omega @ V_{GS} = 4.5 V$ $R_{DS(ON)} = 0.100 \Omega @ V_{GS} = 2.5 V.$
- Low gate charge (3.5nC typical).
- High performance trench technology for extremely low R_{DSION}.
- High power and current handling capability.





Absolute Maximum Ratings T_A = 25°C unless otherwise noted Symbol Parameter Units Ratings V_{DSS} **Drain-Source Voltage** 20 V V_{GSS} Gate-Source Voltage <u>+</u>8 V 1.7 I_{D} Drain Current - Continuous А (Note 1a) - Pulsed 8 P_D Power Dissipation for Single Operation 0.5 W (Note 1a) (Note 1b) 0.46 TJ, Tsta Operating and Storage Junction Temperature Range -55 to +150 °C **Thermal Characteristics** Thermal Resistance, Junction-to-Ambient (Note 1a) 250 °C/W $R_{\theta JA}$ R_{AJC} Thermal Resistance, Junction-to-Case (Note 1) 75 °C/W Package Outlines and Ordering Information **Device Marking** Device **Reel Size Tape Width** Quantity 335 FDN335N 7" 8mm 3000 units

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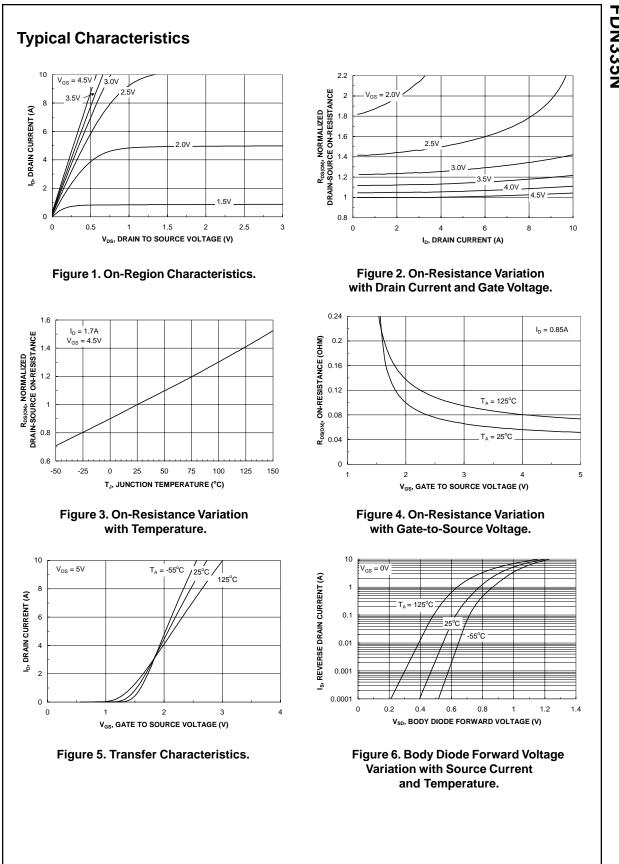
| Symbol | Parameter | Test Conditions | Min | Тур | Max | Units |
|----------------------------------|--|---|-------------|-------------------------|-------------------------|---------|
| Off Char | acteristics | | | | | |
| BV _{DSS} | Drain-Source Breakdown Voltage | $V_{GS} = 0 V, I_D = 250 \mu A$ | 20 | | ĺ | V |
| <u>Δ</u> BVbss ΔTJ | Breakdown Voltage Temperature Coefficient | $I_D = 250 \ \mu$ A,Referenced to 25°C | | 14 | | mV/∘C |
| I _{DSS} | Zero Gate Voltage Drain Current | V _{DS} = 16 V, V _{GS} = 0 V | | | 1 | μA |
| I _{GSSF} | Gate-Body Leakage Current, Forward | $V_{GS} = 8 \text{ V}, V_{DS} = 0 \text{ V}$ | | | 100 | nA |
| I _{GSSR} | Gate-Body Leakage Current, Reverse | $V_{GS} = -8 \text{ V}, V_{DS} = 0 \text{ V}$ | | | -100 | nA |
| On Char | acteristics (Note 2) | | | | | |
| V _{GS(th)} | Gate Threshold Voltage | $V_{DS} = V_{GS}, I_D = 250 \ \mu A$ | 0.4 | 0.9 | 1.5 | V |
| $\Delta VGS(th)$ ΔT_J | Gate Threshold Voltage Temperature Coefficient | $I_D = 250 \ \mu A$, Referenced to 25°C | | -3 | | mV/∘C |
| R _{DS(ON)} | Static Drain-Source On-Resistance | $ \begin{array}{l} V_{GS} = 4.5 \ V, \ I_D = 1.7 \ A \\ V_{GS} = 4.5 \ V, \ I_D = 1.7 \ A, \\ T_J = 125^{\circ}C \\ V_{GS} = 2.5 \ V, \ I_D = 1.5 \ A \end{array} $ | | 0.055 0.079 0.078 | 0.070 0.120 0.100 | Ω |
| I _{D(on)} | On-State Drain Current | $V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$ | 8 | | | Α |
| g fs | Forward Transconductance | $V_{DS} = 5 V, I_D = 1.5 A$ | | 7 | | S |
| Dynamic | Characteristics | | | | | |
| C _{iss} | Input Capacitance | $V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz | | 310 | | pF |
| C _{oss} | Output Capacitance | | | 80 | | pF |
| C _{rss} | Reverse Transfer Capacitance | | | 40 | | pF |
| Switchin | g Characteristics (Note 2) | | | | | |
| t _{d(on)} | Turn-On Delay Time | $V_{DD} = 10 \text{ V}, I_D = 1 \text{ A},$ | 1 | 5 | 15 | ns |
| tr | Turn-On Rise Time | V_{GS} = 4.5 V, R_{GEN} = 6 Ω | | 8.5 | 17 | ns |
| t _{d(off)} | Turn-Off Delay Time | - | | 11 | 20 | ns |
| t _f | Turn-Off Fall Time | - | | 3 | 10 | ns |
| Qg | Total Gate Charge | $V_{DS} = 10 \text{ V}, I_{D} = 1.7 \text{ A},$ | | 3.5 | 5 | nC |
| Q _{gs} | Gate-Source Charge | V _{GS} = 4.5 V, | | 0.55 | | nC |
| Q _{gd} | Gate-Drain Charge | | | 0.95 | | nC |
| Drain-So | urce Diode Characteristics a | and Maximum Ratings | | | | |
| l _s | Maximum Continuous Drain-Source | | | | 0.42 | А |
| V _{SD} | Drain-Source Diode Forward Voltage | $V_{GS} = 0 V, I_S = 0.42 A$ (Note 2) | | 0.7 | 1.2 | V |
| surface of the d | sum of the junction-to-case and case-to-ambient rain pins. R_{BUC} is guaranteed by design while R_{BCA} is a 250°C/W when P b) 2 | | erence is o | defined as t | he solder m | ounting |

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mounted on a 0.02 in² Pad of 2 oz. Cu. Scale 1 : 1 on letter size paper

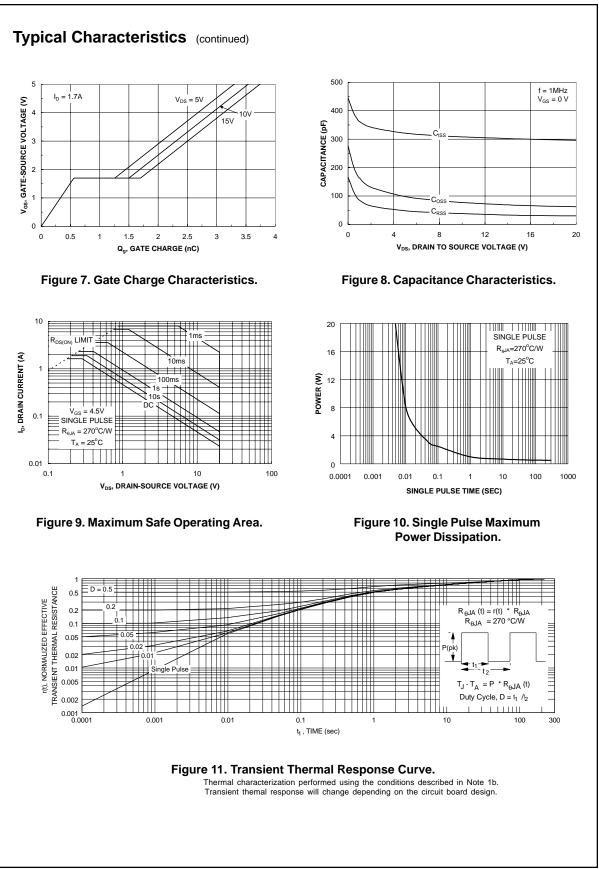
2: Pulse Test: Pulse Width $\leq 300~\mu\text{s},~\text{Duty}~\text{Cycle} \leq 2.0\%$

FDN335N



FDN335N Rev. C

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PRODUCT STATUS DEFINITIONS

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| Datasheet Identification | Product Status | Definition |
|--------------------------|---------------------------|---|
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| | • | Rev. F1 |